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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In the Patent Application of

James J. Synder et al.

**Application No.: 10/672,889**

Filed: September 26, 2003

**For: METHOD AND APPARATUS FOR  
DETERMINING THE WAVELENGTH OF  
AN INPUT LIGHT BEAM**

**Group Art Unit: 2877**

**Examiner: MICHAEL A LYONS**

**Confirmation No.: 9565**

## SECOND INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

**Sir:**

In accordance with the duty of disclosure as set forth in 37 C.F.R. § 1.56, the accompanying information is being submitted in accordance with 37 C.F.R. §§ 1.97 and 1.98.

Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed. However, copies of the listed U.S. patents and U.S. patent application publications are not enclosed since it is no longer required according to the July 11, 2003 waiver of the requirement for copies of cited U.S. patents and U.S. patent application publications in national patent applications filed after June 30, 2003 and international applications entering the national stage under 35 U.S.C. § 371 after June 30, 2003.

The documents are being submitted within three (3) months of the filing or entry of the national stage of this application or before the first Office Action on the merits, whichever is later. Since these documents are being filed within the time period set forth in 37 C.F.R. § 1.97(b), no fee or statement is required.

**SECOND** Information Disclosure Statement

Application No. 10/672,889

Attorney's Docket No. 033806-010

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To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initialed copy of this form be returned to the undersigned.

Respectfully submitted,

BUCHANAN INGERSOLL PC

Date November 17, 2005

By: 

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# **SECOND INFORMATION DISCLOSURE STATEMENT BY APPLICANT**

(use as many sheets as necessary)

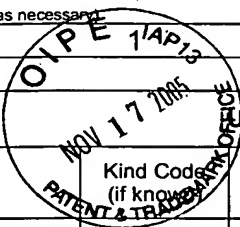
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**Complete if Known**

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|-------------------------------|------------------------|
| <b>Application Number</b>     | 10/672,889             |
| <b>Filing Date</b>            | September 26, 2003     |
| <b>First Named Inventor</b>   | James J. Synder et al. |
| <b>Examiner Name</b>          | MICHAEL A LYONS        |
| <b>Attorney Docket Number</b> | 033806-010             |

**U.S. PATENT DOCUMENTS**

| Examiner Initials | Document Number | Kind Code (if known) | Name of Patentee or Applicant of Cited Document | Issue/Publication Date (MM-DD-YYYY) |
|-------------------|-----------------|----------------------|---|-------------------------------------|
|                   |                 |                      |   |                                     |
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**FOREIGN PATENT DOCUMENTS**

| Examiner Initials | Document Number | Kind Code (if known) | Country | Date of Publication (MM-DD-YYYY) | STATUS      |                     |                    |               |      |          |               |
|-------------------|-----------------|----------------------|---------|----------------------------------|-------------|---------------------|--------------------|---------------|------|----------|---------------|
|                   |                 |                      |         |                                  | Translation | Partial Translation | Eng. Lang. Summary | Search Report | IPER | Abstract | Cited in Spec |
|                   |                 |                      |         |                                  |             |                     |                    |               |      |          |               |
|                   |                 |                      |         |                                  |             |                     |                    |               |      |          |               |
|                   |                 |                      |         |                                  |             |                     |                    |               |      |          |               |
|                   |                 |                      |         |                                  |             |                     |                    |               |      |          |               |

**NON-PATENT LITERATURE DOCUMENTS**

| Examiner Initials | Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published. |
|-------------------|---|
|                   | Snyder, J.J., "Algorithm for fast digital analysis of interference fringes", <i>Applied Optics</i> 19, 1223 (1980).   |
|                   | J.H. Bruing, "Fringe Scanning Interferometers", in <i>Optical Shop Testing</i> , Daniel Malacara, ed. (John Wiley and Sons, New York, 1978) 409-437.  |
|                   | Katherine Creath, "Phase-Measurement Interferometry Techniques," in <i>Progress in Optics XXXVI</i> , E. Wolf, ed. (North-Holland, Amsterdam, 1988), 349-393.   |
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Examiner Signature

Date Considered

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with M.P.E.P. § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.